

N-71-2R
OWNED
032603

JOURNAL OF **CRYSTAL GROWTH**

Journal of Crystal Growth 169 (1996) 20–26

Growth of cadmium–zinc telluride crystals by controlled seeding “contactless” physical vapor transport

W. Palosz ^{a,*}, K. Grasza ^{b,2}, D. Gillies ^a, G. Jerman ^a

^a NASA / Marshall Space Flight Center, ES75, Huntsville, Alabama 35812, USA

^b Institute of Physics, Polish Academy of Sciences, Warsaw, Poland

Received 17 January 1996; accepted 15 April 1996



Journal of Crystal Growth

EDITORIAL BOARD

M. SCHIEBER (Principal Editor)
Dept. Mater. Sci., School Appl. Sci. & Technol.
Hebrew University, Jerusalem 91904, Israel
Telefax: +972-2-666 804

R. KERN
CRM-C, CNRS, Campus Luminy, Case 913
F-13288 Marseille Cedex 9, France
Telefax: +33-91-418 916

R.S. FEIGELSON
Ctr. Materials Res., 105 McCullough Bldg.
Stanford Univ., Stanford, CA 94305-4045, USA
Telefax: +1-415-723 3044

T. NISHINAGA
Dept. Electron. Eng., Univ. of Tokyo
7-3-1, Hongo, Bunkyo-ku, Tokyo 113, Japan
Telefax: +81-3-5684-3974

D.T.J. HURLE
H.H. Wills Phys. Lab., Univ. Bristol
Tyndall Avenue
Bristol BS8 1TL, UK

G.B. STRINGFELLOW
Dept. Mater. Sci., 304 EMRO, Univ. of Utah
Salt Lake City, UT 84112, USA
Telefax: +1-801-581 4816

ASSOCIATE EDITORS

A. BARONNET (*Industrial, Biological, Molecular Crystals*)
CRM-C, CNRS, Campus Luminy, Case 913
F-13288 Marseille Cedex 9, France
Telefax: +33-91-418 916

K.W. BENZ (*Microgravity, Electronic Materials*)
Kristallographisches Inst., Universität
Hebelstr. 25, D-79104 Freiburg, Germany
Telefax: +49-761-203 4369

A.A. CHERNOV (*Kinetics of Crystallization, Protein Crystallization*)
Inst. Crystallography, Acad. of Sciences
Leninskii Prospekt, Moscow 117333, Russian Fed.
Telefax: +7-095-135 1011

A.Y. CHO (*Molecular Beam Epitaxy*)
Room IC-323, AT&T Bell Laboratories
Murray Hill, NJ 07974-2070, USA
Telefax: +1-908-582 2043

B. COCKAYNE (*IOCG News*)
School of Metallurgy and Mater.
Univ. Birmingham, P.O. Box 363, Edgbaston, Birmingham
B15 2TT, UK
Telefax: +44-121-471 2207

S.R. CORIELL (*Theory*)
A153 Mater. Natl. Inst. of Standards & Technol.
Gaithersburg, MD 20899-0001, USA

D. ELWELL (*Priority Communications, Superconductivity*)
Hughes Aircraft Company
P.O. Box H, M/S A2408, 500 Superior Avenue
New Port Beach, CA 92658-8908, USA
Telefax: +1-714-759 2868

M.E. GLICKSMAN (*Solidification*)
School of Eng., Mater. Eng. Dept., Rensselaer Polytechnic
Inst., Troy, NY 12180-3590, USA
Telefax: +1-518-276 8554

M.A.G. HALLIWELL (*X-ray Diffraction*)
Philips Analytical X-ray, Lelyweg 1
7602 EA Almelo, The Netherlands

T. HIBIYA (*Oxides, Melt Thermophysical Properties, Microgravity*)
Fundamental Res. Labs., NEC CORPORATION
34, Miyukigaoka, Tsukuba 305, Japan
Telefax: +81-298-566 136

H. KOMATSU (*Proteins Molecular Crystallization, Growth from Solutions*)
Inst. Mater. Res., Tohoku Univ.
Katahira 2-1-1, Sendai 980, Japan
Telefax: +81-22-215 2011

T.F. KUECH (*Thin Films and Electronic and Optical Devices*)
Dept. Chem. Eng., Univ. Wisconsin-Madison
Madison, WI 53706, USA
Telefax: +1-608-265 3782

A. McPHERSON (*Protein Growth*)
Dept. Biochemistry, Univ. of California
Riverside, CA 92521, USA
Telefax: +1-909-787 3790

P.A. MORRIS HOTSENPILLER (*Electrooptical Crystals, Book Reviews, Oxide Thin Films*)
E.I. du Pont de Nemours & Co., Exp. Station
Wilmington, DE 19888-0358, USA
Telefax: +1-302-695 1664

J.B. MULLIN (*Semiconductors*)
EMC, "The Hoo", Brockhill Road
West Malvern, Worcs., WR14 4DL, UK
Telefax: +44-1684-575 591

K. NAKAJIMA (*Liquid and Vapor Phase Epitaxy*)
Integrated Mater. Lab., Fujitsu Labs. Ltd.
Morinosato-Wakamiya 10-1, Atsugi 243-01, Japan
Telefax: +81-462-48 3473

H. OHNO (*Epitaxy*)
Research Inst. of Electrical Commun.
Tohoku Univ., Sendai 980 77, Japan
Telefax: +81-22-217 5553

K. PLOOG (*Molecular Beam Epitaxy*)
Paul-Drude-Inst. für Festkörperelektronik
Hausvogteiplatz 5-7, D-10117 Berlin, Germany
Telefax: +1-49-30-203 77201

F. ROSENBERGER (*Protein Crystallization, Fluid Dynamics*)
Center for Microgravity and Materials Research
Univ. Alabama, Huntsville, AL 35899, USA
Telefax: +1-205-895 6791

R.W. ROUSSEAU (*Solution Growth, Industrial Crystallization*)
School of Chem. Eng., Georgia Inst. of Technol.
Atlanta, GA 30332-0100, USA
Telefax: +1-404-894 2866

K. SATO (*Biocrystallization and Organic Crystals*)
Fac. Appl. Biol. Sci., Hiroshima Univ.
Higashi-Hiroshima 724, Japan
Telefax: +81-824-227 062

L.F. SCHNEEMEYER (*Superconductivity, Oxides, Novel Materials*)
Room 1A-363, AT&T Bell Labs.
Murray Hill, NJ 07974-2070, USA
Telefax: +1-908-582 2521

D.W. SHAW (*Semiconductors, Epitaxy, Devices*)
Texas Instruments Inc., P.O. Box 655936, MS 147
Dallas, TX 75265, USA
Telefax: +1-214-995 7785

I. SUNAGAWA (*Minerals*)
3-54-2 Kashiwa-cho, Tachikawa-shi
Tokyo 190, Japan
Telefax: +81-425-35 3637

G. VAN TENDELOO (*Electron Microscopy, Fullerenes, Superconductivity*)
University of Antwerp, RUCA
Groenenborgerlaan 171, B-2020 Antwerp, Belgium
Telefax: +32-3-2180 217

A.F. WITT (*Semiconductor Crystals*)
Dept. of Metall. & Mater. Sci., Massachusetts
Inst. of Technol., Cambridge, MA 02139, USA
Telefax: +1-617-253 5827

A. ZANGWILL (*Theory (Epitaxy)*)
School of Physics, Georgia Inst. of Technol.
Atlanta, GA 30332, USA
Telefax: +1-404-894 9958

Scope of the Journal

Experimental and theoretical contributions are invited in the following fields: Theory of nucleation and growth, molecular kinetics and transport phenomena, crystallization in viscous media such as polymers and glasses. Crystal growth of metals, minerals, semiconductors, magnetics, inorganic, organic and biological substances in bulk or as thin films. Apparatus, instrumentation and techniques for crystal growth, and purification methods. Characterization of single crystals by physical and chemical methods.

Abstracted/Indexed in:

Aluminium Industry Abstracts; Chemical Abstracts; Current Contents: Physical, Chemical and Earth Sciences; Ei Compendex Plus; Engineered Materials Abstracts; Engineering Index; INSPEC; Metals Abstracts; Physics Briefs.

Subscription Information 1996

Volumes 158-169 of Journal of Crystal Growth (ISSN 0022-0248) are scheduled for publication. (Frequency: semimonthly.) Prices are available from the publishers upon request. Subscriptions are accepted on a prepaid basis only. Issues are sent by SAL (Surface Air Lifted) mail wherever this service is available. Airmail rates are available upon request. Please address all enquiries regarding orders and subscriptions to:

Elsevier Science B.V., Order Fulfillment Department
P.O. Box 211, 1000 AE Amsterdam, The Netherlands
Tel: +31 20 485 3642; Fax: +31 20 485 3598

Claims for issues not received should be made within six months of our publication (mailing) date.

US mailing notice - Journal of Crystal Growth (ISSN 0022-0248) is published semimonthly by Elsevier Science B.V., Molenwerf 1, P.O. Box 211, 1000 AE Amsterdam, The Netherlands. Annual subscription price in the USA is US \$6535 (valid in North, Central and South America only), including air speed delivery. Periodicals postage paid at Jamaica NY 11431. US postmasters: Send address changes to Journal of Crystal Growth, Publications Expediting, Inc., 200 Meacham Avenue, Elmont NY 11003. Airfreight and mailing in the USA by Publications Expediting.

© The paper used in this publication meets the requirements of ANSI/NISO Z39.48-1992 (Permanence of Paper)

PRINTED IN THE NETHERLANDS

North-Holland, an imprint of Elsevier Science



ELSEVIER

Journal of Crystal Growth 169 (1996) 20–26

JOURNAL OF **CRYSTAL
GROWTH**

Growth of cadmium–zinc telluride crystals by controlled seeding “contactless” physical vapor transport

W. Palosz^{a,*}, K. Grasza^{b,2}, D. Gillies^a, G. Jerman^a

^a NASA / Marshall Space Flight Center, ES75, Huntsville, Alabama 35812, USA

^b Institute of Physics, Polish Academy of Sciences, Warsaw, Poland

Received 17 January 1996; accepted 15 April 1996

Abstract

Bulk crystals of cadmium–zinc telluride, 23 mm in diameter and up to 45 grams in weight were grown. Controlled seed formation procedure was used to limit the number of grains in the crystal. Most uniform distribution of ZnTe in the crystals was obtained using excess (Cd + Zn) pressure in the ampoule.

1. Introduction

Cadmium–zinc telluride crystals can be used as substrates for HgTe-based infrared detectors and as room-temperature γ -ray detectors. By appropriate selection of ZnTe content in the crystals, the lattice constants of the substrate and of the active epilayer can be matched giving improved crystallographic perfection and related performance of the devices [1]. Nuclear detectors fabricated from cadmium–zinc telluride show improved, relative to CdTe, energy resolution [2].

Crystals of (Cd,Zn)Te can be grown by physical vapor transport (PVT) at relatively low temperatures

and in the absence of a second condensed phase. Under such conditions, material with improved crystallographic perfection and purity relative to those in melt grown crystals may be obtained. In this work we investigate the growth of (Cd,Zn)Te crystals by a self-nucleation “contactless” PVT technique using a special seed selection procedure. This method has proved successful in growing large, high quality crystals of the related material, CdTe [3,4]. However, growth of a ternary crystal by PVT poses distinctive thermochemical and kinetic complications as compared to related binary systems [5,6]. The current work has been undertaken in order to evaluate the capabilities and limitations of the “contactless” techniques for growing ternary, cadmium–zinc telluride bulk crystals.

2. Experimental procedures

Cadmium–zinc telluride ($\text{Cd}_{1-x}\text{Zn}_x\text{Te}$) source materials were synthesized as described in our earlier

* Corresponding author. Fax: +1 205 544 8762; E-mail: palosz@ssl.msfc.nasa.gov.

¹ NRC Senior Research Associate, currently with Universities Space Research Association.

² Present address: Brimrose Corporation, Baltimore, Maryland 21236, USA.

Table 1
Crystal growth experimental parameters

Initial composition of the source, X_0	0.04, 0.21
Range of $T(\text{source})$:	
without excess (Cd + Zn)	880°C–930°C
with excess (Cd + Zn)	990–1050°C
Excess component pressure (at $T(\text{source})$)	0.03–0.7 atm H_2 or 0.1–0.2 atm (Cd + Zn) + 0.04 atm H_2
Duration of seed selection stage	2–5 days
Average crystal growth rate	1–2.5 mm per day
Post-growth cool-down	$T(\text{source}) \rightarrow 100^\circ\text{C}$ in 3 h

work [6]. 50–60 g of pre-synthesized source was thermally pre-treated [6], then sealed and pre-compacted at about 850°C under hydrogen atmosphere to a relative density of about 70%. The compacted material was loaded (with pre-determined amount of elemental cadmium when desired) into a growth ampoule of the type used earlier [3]. The ampoule was assembled, evacuated, and back-filled with the desired amount of hydrogen and sealed. Crystal growth experimental parameters are listed in Table 1.

Composition profiles were obtained using electron microprobe analysis techniques. The spatial resolution of the measurements was 40 micrometers. The combined composition (X) uncertainty (resulting from the beam current instabilities, local surface non-planarity, and misalignment of the sample and standards relative to the beam direction) was estimated at about 3% or less.

3. Experimental results

3.1. Growth without excess constituent element

Fig. 1 illustrates consecutive stages of the growth process [3,4]. The initial source (Fig. 1a) undergoes a local recrystallization in the (non-uniform) thermal field, what leads to formation of a cone with a crystal grain (seed) at its tip (Fig. 1b). Further development of the cone and seed leads to a contact and attachment of the seed crystal to the pedestal (Fig. 1c). After a proper change of the thermal field (by displacing the ampoule [3]) the seed separates from the source (Fig. 1d) and the crystal growth proceeds (Fig. 1e). Photographs of the source and of the seed developed on top of the source (stage (b) in Fig. 1) are shown in Fig. 2a and 2b, respectively. The seed is bound primarily by {110} and {111} facets. Composition profiles across the seed are shown in Fig. 3a

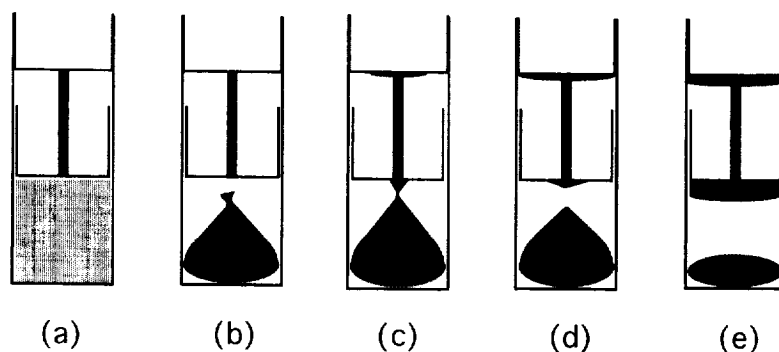


Fig. 1. Schematic representation of the consecutive stages of the nuclei development and crystal growth.



Fig. 2. The source (a) and the crystal (b) formed on the source tip. $X_0 = 0.04$, no excess constituent element.

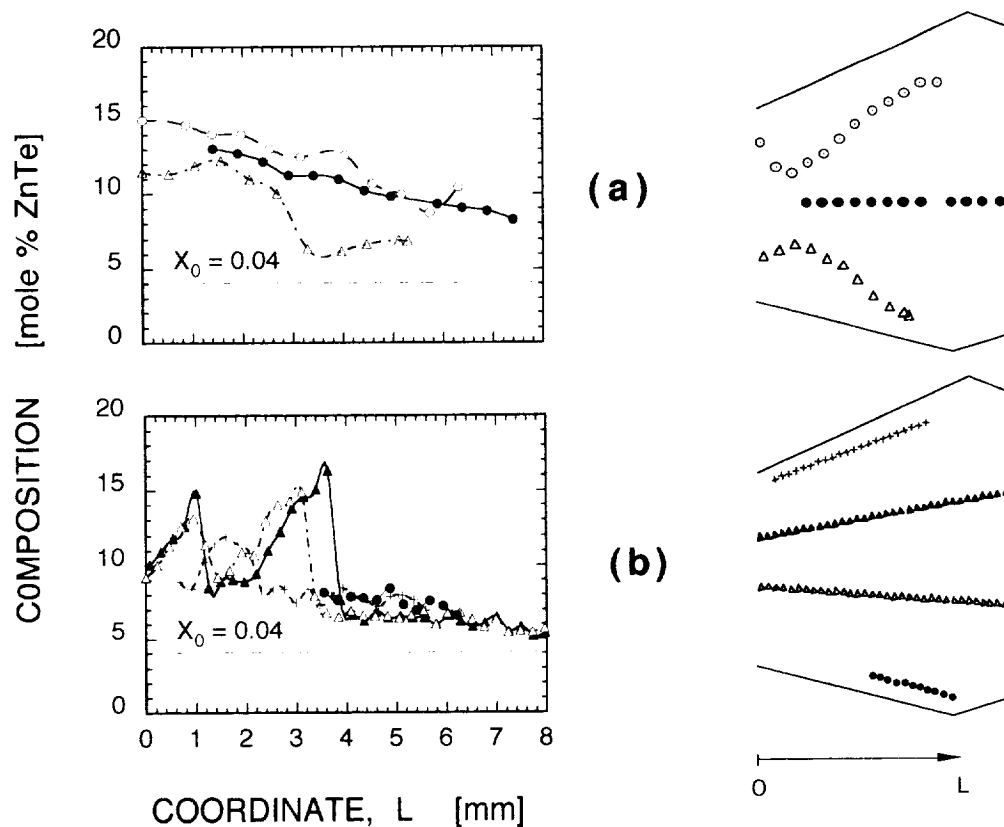


Fig. 3. Composition profiles in the seed crystal shown in Fig. 2: (a) on the surface; (b) in the bulk mid-plane. Scanning paths are shown on the right. L is the position along the path.

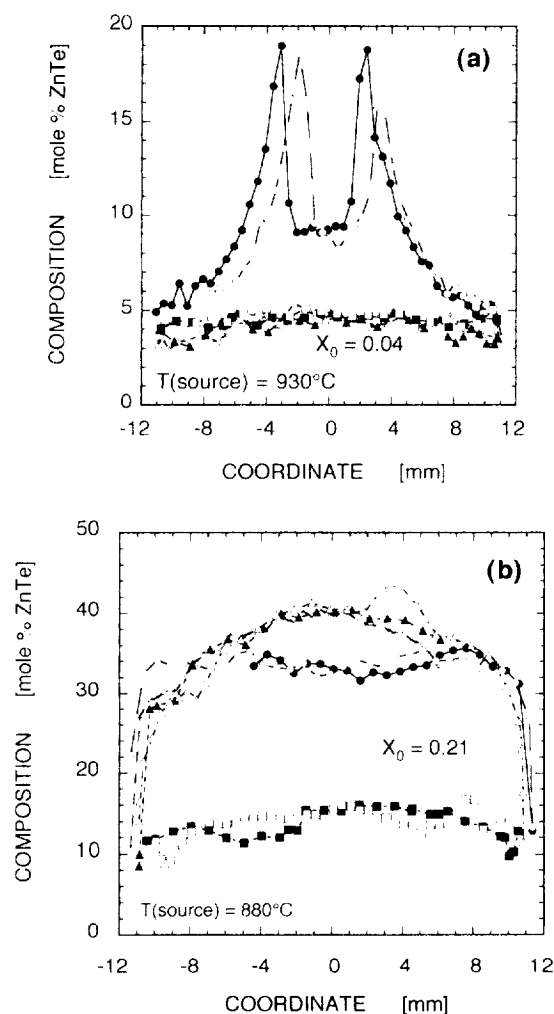


Fig. 4. Lateral composition profiles of the crystals grown without intentional addition of constituent element(s) to the ampoule: z is the distance from the pedestal, full symbols and open symbols depict scans along x and y , respectively. (a) $X_0 = 0.04$: (●, ○) $z = 0.3$ mm; (▲, △) $z = 6$ mm; (■, □) $z = 12$ mm. (b) $X_0 = 0.21$: (●, ○) $z = 0.3$ mm; (×) $z = 1.5$ mm; (▲, △) $z = 3.5$ mm; (■, □) $z = 12$ mm.

and 3b on the surface and in the bulk of the seed, respectively. The composition of the seed is highly non-uniform and up to four times higher than the

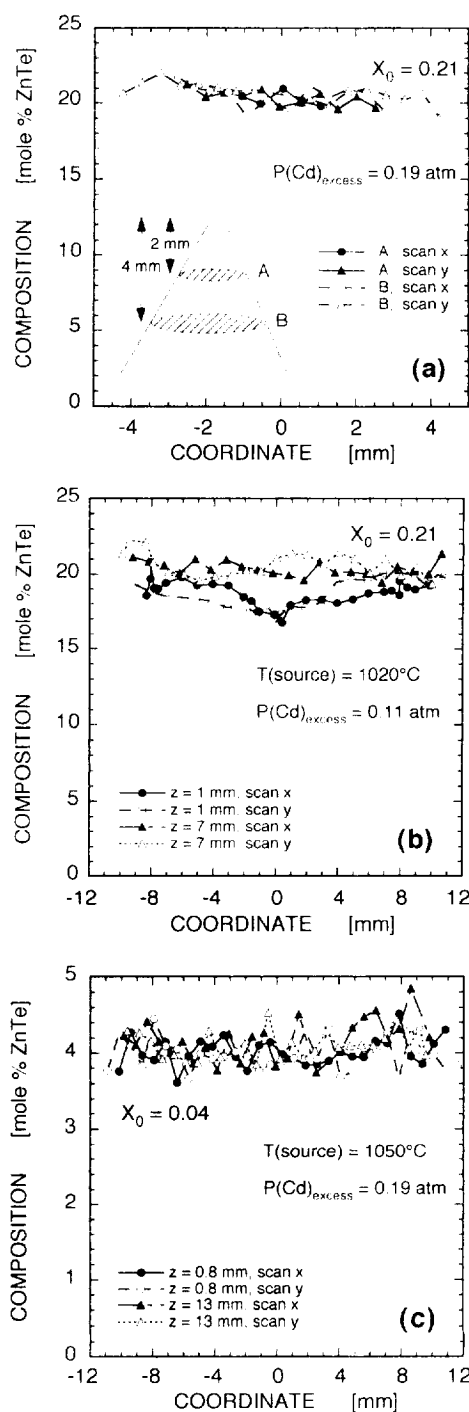


Fig. 5. Lateral compositions of the source tip (seed) and crystals grown under excess (Cd + Zn) pressure. (a) The source, $X_0 = 0.21$ (the inset shows the investigated cross sections of the source); (b) crystal, $X_0 = 0.21$; (c) crystal, $X_0 = 0.04$.

average composition of the source $X_0 = 0.04$. The observed non-uniformity of the ZnTe distribution after the source compacting/recrystallization is consistent with the results of our earlier work [5,6]. Fig. 4a shows lateral composition profiles of a crystal grown from $X_0 = 0.04$ source without intentional excess constituent in the vapor phase. The composition profiles of the first grown part of the crystal ($z = 0.3$ mm, where z is the distance from the pedestal) are highly non-uniform and reflect the compositional non-uniformity of the seed: the composition in the middle of the cross section corresponds to the location where the seed attached itself to the pedestal (stage (c) in Fig. 1). Subsequent, laterally grown parts of the crystal enriched in ZnTe (the peaks in Fig. 4a) are apparently due to high concentrations of zinc on top of the source [6]. The composition becomes relatively uniform in further parts of the crystal (Fig. 4a, $z = 6$ and 12 mm). Fig. 4b shows lateral composition profiles of a crystal grown from $X_0 = 0.21$ source. The compositional non-uniformities in the initially grown part of the crystal (Fig. 4b, $z = 0.3$ mm) are relatively less pronounced than corresponding profiles for $X_0 = 0.04$ (Fig. 4a). However, substantial lateral non-uniformities are observed in different parts of the crystal. In addition, axial composition non-uniformity of the crystal is very high, the composition varies (Fig. 4b) from 200% to 50% of the initial composition of the source ($X_0 = 0.21$).

3.2. Growth under excess (Cd + Zn) pressure

Vaporization of cadmium–zinc telluride is essentially a non-congruent process: mole fraction of the more volatile component (Cd) is higher in the vapor

than in the solid. Preferential vaporization of cadmium relative to that of zinc leads to a higher concentration of CdTe on the crystal–vapor relative to that at the source–vapor interface. As a consequence, progressive accumulation of the less volatile component (ZnTe) at the source–vapor interface leads to subsequent composition gradients in the source and in the growing crystal [6]. This process can be suppressed by an appropriate adjustment of the composition of the vapor: local thermodynamic equilibria combined with mass continuity requirements under steady state conditions lead to such redistribution of the vapor species that congruent transfer of the material becomes possible [5,6]. As expected, growth under excess metal pressure conditions leads to improved homogeneity of our cadmium–zinc telluride crystals. Fig. 5a shows lateral composition profiles of two cross sections of the source top after compacting/recrystallization (stage (b), Fig. 1) of $X_0 = 21$ material under excess metal pressure conditions. The composition of the cross sections is quite uniform and close to the initial composition of the source X_0 . Lateral composition profiles of crystals grown under excess (Cd + Zn) pressure are shown in Figs. 5b and 5c. Both axial and lateral distributions of ZnTe in the crystals are fairly uniform and close to X_0 . This is a considerable improvement relative to crystals grown without intentional non-stoichiometry of the vapor (Figs. 4a and 4b).

3.3. Crystals

A representative crystal grown in this work is shown in Fig. 6a. In general, the (Cd,Zn)Te crystals are similar in appearance to CdTe crystals grown by

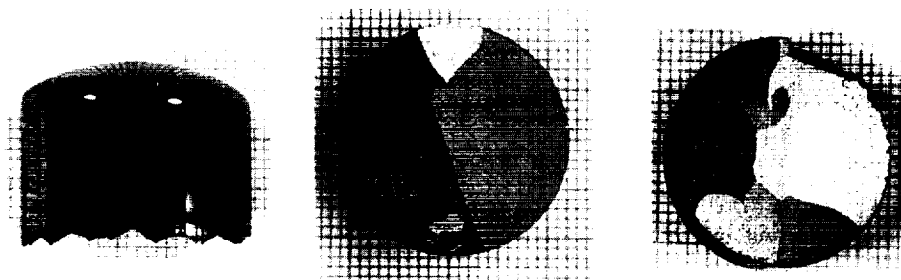


Fig. 6. Crystals. (a) Overall view. (b), (c) Cross sections of a crystal of $X \approx 0.04$ (no excess pressure) and $X \approx 0.2$ (excess $P(\text{Cd} + \text{Zn})$), respectively.

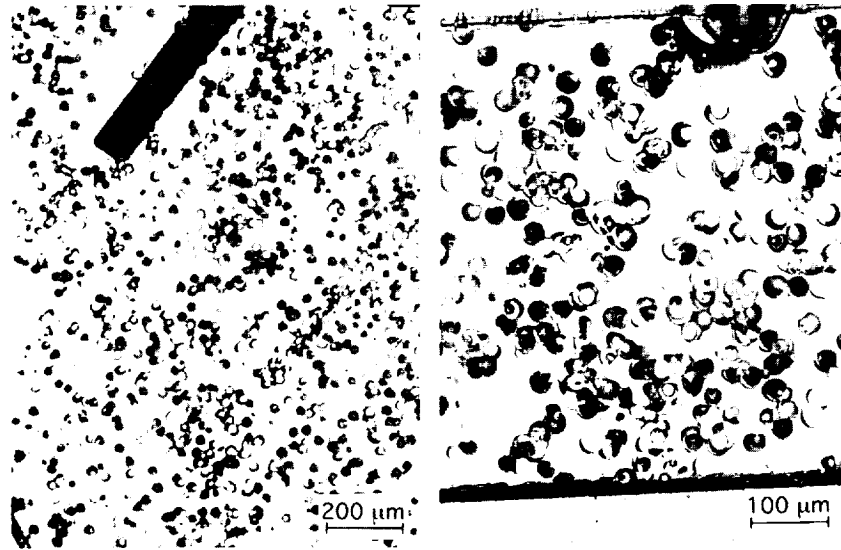


Fig. 7. Photomicrographs of etched (Nakagawa etch [7], Cd(111) surface) crystals of $X = 0.04$ grown (a) without, and (b) with excess (Cd + Zn) pressure.

the “contactless” technique [3]. The nuclei selection and control is, however, more difficult and more grains may form during growth of cadmium–zinc telluride crystals. Large single-crystalline grains can, however, be obtained (Figs. 6b and 6c). EPD values are about 10^5 cm^{-2} (Fig. 7a and 7b). No apparent difference in EPD values was found between crystals grown with and without excess (Cd + Zn). Crystals grown with excess metal were relatively brittle and had a tendency to break into a few pieces during cutting by a wire saw. Similar tendency to cracking was found in CdTe crystals grown under excess Cd pressure [3]. Cracking of (Cd,Zn)Te crystals observed by Ruault et al. [8] has been interpreted as a result of a phase separation/second phase formation

at lower temperatures [9]. Laue back-reflection diffraction patterns of our crystals do not, however, show any traces of a second phase in the material (Fig. 8a and 8b).

4. Conclusions

The technique of “contactless” PVT with nucleus pre-formation can be used to grow bulk $\text{Cd}_{1-X}\text{Zn}_X\text{Te}$ crystals both with lower ($X \approx 0.04$) and higher ($X \approx 0.2$) zinc telluride concentrations. With a careful control of the process, large single-crystalline grain(s) can be obtained. Our experience with other ternary systems indicates that further im-

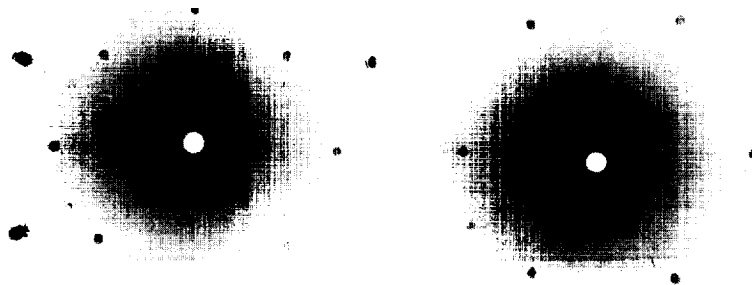


Fig. 8. Laue back-reflection diffraction patterns. (a) $X = 0.04$, (001) surface; (b) $X = 0.2$, (111) surface.

provement (larger grains and even single crystals) is possible with a more elaborate seed-selection process and better adjustment of the growth parameters and procedures. The best compositional homogeneity can be obtained for crystals grown under excess (Cd + Zn) pressure in the ampoule. The associated increased brittleness of the crystals could, possibly, be reduced by growth under modified thermophysical conditions (if caused by growth instabilities) or by a post-growth annealing under different (Te-rich?) atmosphere (if caused by excess metal in the lattice). Without the intentional addition of a constituent element a reasonably uniform distribution of zinc telluride in a part of the crystal can also be obtained for low ZnTe content in the source. Preliminary crystallographic characterization of the crystals shows a moderate etch pit density and no apparent presence of a second phase. More extensive crystallographic characterization of the crystals using synchrotron radiation will be presented in a separate publication [10].

Acknowledgements

The authors are pleased to acknowledge the support of this work by the National Research Council

Associateship Programs. The support of the Microgravity Science and Applications Division of the National Aeronautics and Space Administration is also gratefully acknowledged.

References

- [1] A. Szilagyí and M.-N. Grimbergen, *J. Crystal Growth* 86 (1988) 912.
- [2] J.F. Buttler, C.L. Lingren and F.P. Doty, *IEEE Trans. Nucl. Sci.* 39 (1992) 605.
- [3] K. Graszka, U. Zuzga-Graszka, A. Jedrzejczak, R.R. Galazka, J. Majewski, A. Szadkowski and E. Grodzicka, *J. Crystal Growth* 123 (1992) 519.
- [4] K. Graszka, *J. Crystal Growth* 146 (1995) 65.
- [5] W. Palosz, S.L. Lehoczky and F.R. Szofran, *J. Crystal Growth* 148 (1995) 49.
- [6] W. Palosz, F.R. Szofran and S.L. Lehoczky, *J. Crystal Growth* 148 (1995) 56.
- [7] K. Nakagawa, K. Maeda and S. Takeuchi, *Appl. Phys. Lett.* 34 (1979) 574.
- [8] M.-O. Ruault, O. Kaitasov, R. Triboulet, J. Crestou and M. Gasgnier, *J. Crystal Growth* 143 (1994) 40.
- [9] A. Marbeuf, R. Druilhe, R. Triboulet and G. Patriarche, *J. Crystal Growth* 117 (1992) 10.
- [10] W. Palosz et al., in preparation.

Journal of Crystal Growth

Instructions to Authors (short version)

Submission of papers

Manuscripts (one original + two copies), should be sent to a member of the Editorial Board or preferably to an appropriate subject Associate Editor. Priority communications should be sent to D. Elwell. News or announcements should be submitted through the Principal Editor; a duplicate should be sent directly to Elsevier Science B.V., address given below.

Original material. Submission of a manuscript implies it is not being simultaneously considered for publication elsewhere and that the authors have obtained the necessary authority for publication.

Types of contributions

Original research papers, Letters to the Editors and Priority communications are welcome. They should contain an Abstract (of up to 200 words) and a Conclusions section, which particularly in the case of theoretical papers translates the results into terms readily accessible to most readers.

As a guideline: *experimental papers* should not be longer than 16 double-spaced typed pages, and 8 figures + tables; for *theoretical papers* a maximum of 20 pages and 10 figures + tables is suggested.

Letters and *Priority communications* should not be longer than 5 double-spaced typed pages, and 3 figures + tables. They will be given priority in both the refereeing and production processes. The faster production schedule may preclude sending proofs of Letters and Priority communications to authors.

Manuscript preparation

Contributions may be written in English, French or German. They should have an abstract in English. The paper copies of the text should be prepared with double line spacing and wide margins, on numbered sheets.

Structure. Please adhere to the following order of presentation: Article title, Author(s), Affiliation(s), Abstract, PACS codes and keywords, Main text, Acknowledgements, Appendices, References, Figure captions, Tables.

Corresponding author. The name, complete postal address, telephone and fax numbers and the e-mail address of the corresponding author should be given on the first page of the manuscript.

Classification codes/keywords. Please supply one to four classification codes (PACS and/or MSC) and up to six keywords of your own choice that describe the content of your article in more detail.

References. References to other work should be consecutively numbered in the text using square brackets and listed by number in the Reference list. Please refer to the more detailed instructions for examples.

Illustrations

Illustrations should also be submitted in triplicate: one master set and two sets of copies. The *line drawings* in the master set should be original laser printer or plotter output or drawn in black india ink, with careful lettering, large enough (3–5 mm) to remain legible after reduction for printing. The *photographs* should be originals, with somewhat more contrast than is required in the printed version. They should be unmounted unless part of a composite figure. Any scale markers should be inserted on the photograph itself, not drawn below it.

Colour plates. Figures may be published in colour, if this is judged essential by the Editor. The Publisher and the author will each bear part of the extra costs involved. Further information is available from the Publisher.

After acceptance

Important. When page proofs of the accepted manuscripts are made and sent out to authors, this is in order to check that no undetected errors have arisen in the typesetting (or file conversion) process. At the proof stage only printer's errors may be corrected. No changes in, or additions to, the edited manuscript will be accepted.

Notification. The authors will receive the final answer of acceptance or rejection from the Office of the Principal Editor and will be invited to supply an electronic version of the accepted text, if this is not already available.

Copyright transfer. In the course of the production process you will be asked to transfer the copyright of the article to the Publisher. This transfer will ensure the widest possible dissemination of information.

Electronic manuscripts

The Publisher welcomes the receipt of an electronic version of your accepted manuscript. If there is not already a copy of this (on diskette) with the journal editor at the time the manuscript is being refereed, you will be asked to send a file with the text of the accepted manuscript directly to the Publisher by e-mail or on diskette (allowed formats 3.5" or 5.25" MS-DOS, or 3.5" Macintosh) to the address given below. (When e-mailing a non-ASCII word-processor file, you should encode it, e.g. with UUENCODE or BinHex, so as to retain all formatting codes.) The name and version of the word-processing program and the type of operating system should always be indicated. Please note that no deviations from the version accepted by the Editor of the journal are permissible without the prior and explicit approval by the Editor. Such changes should be clearly indicated on an accompanying printout of the file.

Author benefits

No page charges. Publishing in Journal of Crystal Growth is free.

Free offprints. The corresponding author will receive 50 offprints free of charge. An offprint order form will be supplied by the Publisher for ordering any additional paid offprints.

Discount. Contributors to Elsevier Science journals are entitled to a 30% discount on all Elsevier Science books.

Further information (after acceptance)

Elsevier Science B.V., J. Crystal Growth
Issue Management Physics
and Materials Science
P.O. Box 2759, 1000 CT Amsterdam
The Netherlands
Fax: +31 20 485 2319/+31 20 485 2704
E-mail: matsci-de-f@elsevier.nl

